Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/678,576	MENG ET AL.	
Examiner	**Art Unit**	
James K. Trujillo	2116	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	5/8/2006	JKT
Updated	10/17/2006	JKT
Updated	12/4/2006	JKT